

INTERNATIONAL STANDARD

NORME INTERNATIONALE

BASIC EMC PUBLICATION

PUBLICATION FONDAMENTALE EN CEM

AMENDMENT 2

AMENDEMENT 2

**Electromagnetic compatibility (EMC) –
Part 4-3: Testing and measurement techniques – Radiated, radio-frequency,
electromagnetic field immunity test**

**Compatibilité électromagnétique (CEM) –
Partie 4-3: Techniques d'essai et de mesure – Essai d'immunité aux champs
électromagnétiques rayonnés aux fréquences radioélectriques**



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FOREWORD

This amendment has been prepared by subcommittee 77B: High frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility.

The text of this amendment is based on the following documents:

FDIS	Report on voting
77B/626/FDIS	77B/629/RVD

Full information on the voting for the approval of this amendment can be found in the report on voting indicated in the above table.

The committee has decided that the contents of this amendment and the base publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

CONTENTS

Add the title of Annex J as follows:

Annex J (informative) Measurement uncertainty due to test instrumentation

Add, after Annex I, the following new Annex J:

Annex J (informative)

Measurement uncertainty due to test instrumentation

J.1 General

This annex gives information related to measurement uncertainty (MU) of the test level setting according to the particular needs of the test method contained in the main body of the standard. Further information can be found in [1, 2]¹.

This annex shows an example of how an uncertainty budget can be prepared based upon level setting. Other parameters of the disturbance quantity such as modulation frequency and modulation depth, harmonics produced by the amplifier may also need to be considered in an appropriate way by the test laboratory. The methodology shown in this annex is considered to be applicable to all parameters of the disturbance quantity.

The uncertainty contribution for field homogeneity including test site effects is under consideration.

J.2 Uncertainty budgets for level setting

J.2.1 Definition of the measurand

The measurand is the hypothetical test electric field strength (without an EUT) at the point of the UFA selected according to the process of 6.2.1 step a) and 6.2.2 step a) of this standard.

J.2.2 MU contributors of the measurand

The following influence diagram (see Figure J.1) gives an **example** of influences upon level setting. It applies to both calibration and test processes and it should be understood that the diagram is not exhaustive. The most important contributors from the influence diagram have been selected for the uncertainty budget Tables J.1 and J.2. As a minimum, the contributions listed in Tables J.1 and J.2 shall be used for the calculation of the uncertainty budgets in order to get comparable budgets for different test sites or laboratories. It is noted that a laboratory may include additional contributors in the calculation of the MU, on the basis of its particular circumstances.

¹ Figures in square brackets refer to the reference documents in Clause J.4.